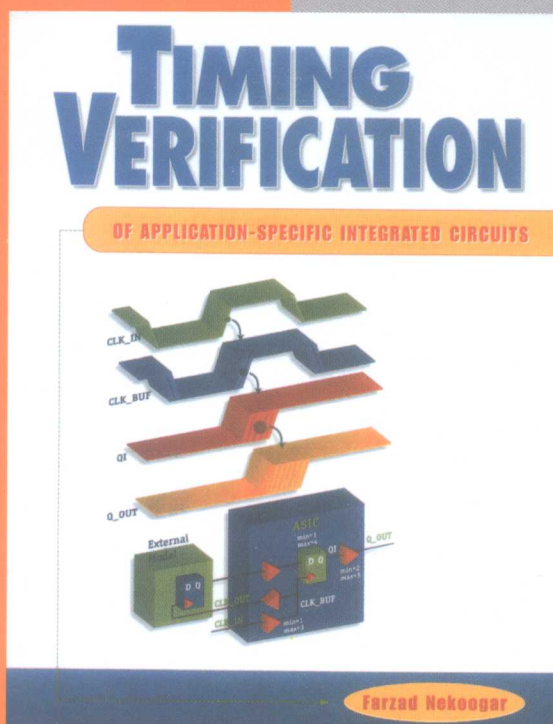


PEARSON

国外大学优秀教材 —— 微电子类系列 (影印版)

Farzad Nekoogar

专用集成电路 时序验证



清华大学出版社

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Timing Verification of
Application-Specific Integrated Circuits

Farzad Nekoogar

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北京

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出版前言

微电子技术是信息科学技术的核心技术之一，微电子产业是当代高新技术产业群的核心和维护国家主权、保障国家安全的战略性产业。我国在《信息产业“十五”计划纲要》中明确提出：坚持自主发展，增强创新能力和核心竞争力，掌握以集成电路和软件技术为重点的信息产业的核心技术，提高具有自主知识产权产品的比重。发展集成电路技术的关键之一是培养具有国际竞争力的专业人才。

微电子技术发展迅速，内容更新快，而我国微电子专业图书数量少，且内容和体系不能反映科技发展的水平，不能满足培养人才的需求，为此，我们系统挑选了一批国外经典教材和前沿著作，组织分批出版。图书选择的几个基本原则是：在本领域内广泛采用，有很大影响力；内容反映科技的最新发展，所述内容是本领域的研究热点；编写和体系与国内现有图书差别较大，能对我国微电子教育改革有所启示。本套丛书还侧重于微电子技术的实用性，选取了一批集成电路设计方面的工程技术用书，使读者能方便地应用于实践。

我们真诚地希望，这套丛书能对国内高校师生、工程技术人员以及科研人员的学习和工作有所帮助，对推动我国集成电路的发展有所促进。也衷心期望着广大读者对我们一如既往的关怀和支持，鼓励我们出版更多、更好的图书。

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2003.9

数字专用集成电路（ASIC）设计是一项覆盖学科内容广泛的系统工程，是将系统、逻辑与性能的设计要求转化为具体的物理版图的过程，也是将产品从抽象的设计要求一步步具体化、直至最终物理实现的过程，涉及系统级、算法级、微架构级、寄存器传输级、门级（网表级）、电路级、版图（GDSII）级等多个设计抽象层次。

成功地设计一款数字集成电路，不仅需要保证逻辑功能正确，还要充分保证各种电特性（如时序、压降、串扰等）因素以及各种商业需求（如面世时间、市场窗口、设计与生产成本等）得到充分的满足。

事实上，电特性方面的需求（尤其是时序因素）成为电路（专用集成电路和FPGA）设计中贯穿从算法级到版图级中的每一个环节都不容轻视的设计考虑。时序因素不仅往往决定了算法级、微架构级以及寄存器传输级设计过程中究竟采用何种做法、策略与技巧，而且将决定后端物理设计各个环节的处理方式和可实现性，并最终决定该芯片制造出之后能否稳定地正常工作。这一切，必然决定了整个芯片的设计难度、设计周期、设计成本与生产成本（如硅片面积、生产工艺等），进而影响到该芯片的市场前景。

正如计算机软件中的任何一种算法求解过程都离不开特定的数据结构实现方式¹，可以毫不夸张地说：**数字集成电路=逻辑+时序**。

中文“时序”一词有两种不同的含义，对应的英文分别是 *sequence*（顺序、因果关系）和 *timing*（时机），前者是对信号间相互控制与处理的顺序和因果关系，属于逻辑的范畴；后者就是这里我们所言及的时序，它是指信号的变化在时间上的相对关系。维基百科全书上对 *timing* 的定义为“*Timing is the spacing of events in time*（即事件在时间上的间隔）”，即信号出现的时机是否恰当。

与逻辑相比较，时序是一个相对新的概念，因而很少有专业书籍论及这一概念及其相关论题。在学术界，*timing* 一词的中文术语尚未统一，也经常被翻译为“定时”、“时机”，甚至是“时间”；在工业界，人们往往习惯于将其称为“时序”。

本书是近年来唯一一本专门讨论时序及时序验证的专著。

本书前两章侧重于介绍时序及时序验证的概念与方法。它首先通过对比功能仿真、动态时序仿真与静态时序验证，指出静态时序验证是唯一快速有效并全面验证芯片是否满足其时序规约的手段；通过电路图和表格方式细致地介绍了时序方面的各种基础概念，如路径延迟、传播延迟、相位偏差、关键路径；解释了内在延迟和外在延迟的各种成因；并以

1 图灵奖 1984 年获得者尼克劳斯·沃思（Niklaus Wirth）曾提出著名的公式：程序=算法+数据结构。

i960 处理器的 EDRAM 接口时序图为例讲述了接口时序分析方法。

本书继而详细地阐述了时钟和时序规约、时序验证的各种概念；讨论了各种时钟方案，如门控时钟、时钟网络/时钟分布结构、多频率时钟和多相位时钟等；细致地讨论了静态时序分析中可以采用的各种手段，如设置无效路径、多周期路径、施加各方面时序约束。

本书后两章分别针对专用集成电路（ASIC）和基于可编程逻辑器件的设计展开时序方面的讨论。

专用集成电路在逻辑综合（即版图设计之前）还没有实际的布局布线信息，因此只能采用较为粗略的连线负载模型进行时序分析，而版图设计之后有了实际的布线结果，因而可以充分考虑各种寄生效应及相应的延迟模型精确地分析时序。本书第三章通过电路延迟模型分析了寄生效应对时序的作用机制；介绍了在 Verilog HDL 代码中标注延迟的各种方法；介绍了设计流程中各环节间用于交换延迟信息的各种标准延迟格式与寄生效应数据格式；讨论了 ASIC 设计过程中如何施加设计规则约束及优化手段；并给出了版图设计之后的信号线电容、电阻以及 RC（电容电阻）延迟的计算方法；探讨了 ASIC 送交生产前的签付检查应当履行的各项检查。

第四章结合最常用的可编程逻辑器件，如 Actel 公司、Altera 公司和 Xilinx 公司的器件，从设计流程、可编程逻辑结构、时序参数、时序分析、HDL 综合、软件开发系统等方面具体讨论了可编程逻辑器件及相关的时序问题。

本书全面地讨论了静态时序验证的各方面内容；全书不仅紧密结合电路图和波形图进行讲解，还结合 Synopsys 公司的逻辑综合和静态时序分析工具讲解如何通过命令加以实现；介绍过程中不仅从理论上阐述了延迟模型，而且注重实践环节，引入了大量实际示例加以深入探讨。相信这种写作风格将促进读者能够更全面、更细致地理解所讲内容，因此本书十分适合于（集成）电路工程师、FPGA 工程师以及（电路板级）硬件设计工程师自学，电子工程和微电子专业高年级本科生和研究生可以将本书用作时序分析与时序验证方面的教材和教学参考书。

孙海平

2009 年 10 月于同济大学嘉定校区

Preface

This book describes the theory and applications of timing verification of application-specific integrated circuits (ASICs). Timing verification is a relatively new concept, which is why most books on digital systems do not cover the issue. This book lays out the fundamental principles of effective timing verification, and it makes good use of the examples that reflect the current issues facing logic designers.

The following items characterize this book:

- ✦ Timing verification as opposed to functional verification is the primary focus. (Functional simulation has been adequately covered in other books.)
- ✦ Principles and techniques as opposed to specific tools are emphasized. Once designers understand the underlying principles of timing analysis, they can apply them with various timing tools.
- ✦ Design flow for deep-submicron ASICs and FPGA designs are fully covered.
- ✦ Numerous design examples and HDL codes to illustrate the concepts discussed in the book are provided.

This book is to be used for self-study by practicing engineers. Design and verification engineers who are working with ASICs and FPGAs will find the book very useful. Upper-level undergraduate and graduate students in electrical engineering can use it as a reference book in design courses in timing analysis and related topics.

The material covered in this book requires some understanding of the Electronic Design Automation (EDA) tools and an initial course in logic design.

The book is organized into two parts:

Part I (chapters 1 and 2) introduces the fundamental concepts involved in timing verification. Including clock definitions, multicycle paths, false paths, and phase-locked loops.

Part II (chapters 3 and 4) covers specific timing issues related to ASICs and FPGAs, respectively.

Chapter 1 gives an overview of timing verification and static timing analysis. It contrasts timing verification with functional verification. Typical goals of timing verification in digital systems are presented. This chapter ends with an example of interface timing analysis.

Chapter 2 introduces the concepts of timing analysis with design examples. It specifically discusses such clocking methods as gated clocks, multifrequency clocks, and multiphase clocks. It introduces the concepts of multicycle paths, false paths, and timing constraints (such as setup, hold, recovery, and pulse width).

Chapter 3 discusses the deep submicron ASIC design flow and application of timing analysis in the design process. It includes discussion of prelayout and postlayout timing verification. The chapter also discusses behavioral and structural RTL coding for timing, synthesis and timing constraint, and the ASIC sign-off checklist. We make the concepts concrete with numerous examples.

Chapter 4 discusses timing concepts in programmable logic-based designs. It covers design flow, timing parameters, timing analysis, and HDL synthesis and software development systems. We present the most commonly used programmable logic devices (Actel, Altera, and Xilinx) and associated timing issues.

Appendices A, B, and C discuss the EDA timing tools of PrimeTime, Pearl, and TimingDesigner respectively.

Appendix D covers some concepts of transistor-level timing verification.

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—Farzad Nekoogar

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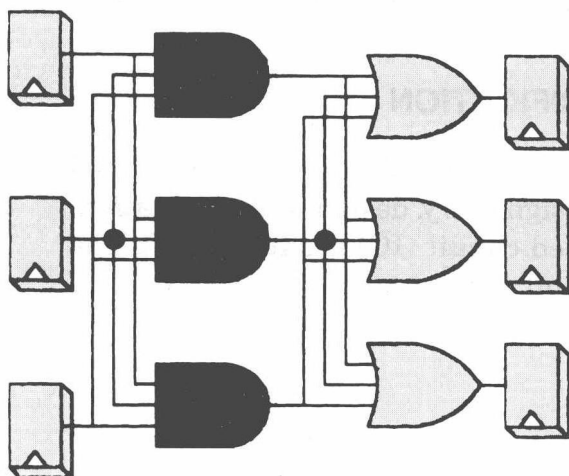
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Introduction to Timing Verification

1.1 INTRODUCTION

In this book we introduce the concept of timing verification of ASICs. The fundamental concepts can be applied to ASIC, field programmable gate array (FPGA), and system-on-a-chip designs. It should be noted that most of the material presented in this book is electronic design automation (EDA)-tool independent. However, any mention of specific commands for Static Timing Verification (STA) is based on the Synopsys PrimeTime static timing analyzer. Also, any mention of a specific synthesis tool or command refers to Synopsys Design Compiler and its related modules.

Overview of some current EDA tools that are used for timing verification can be found in appendices A, B, and C. Also, Verilog-HDL is used throughout the book for hardware description language (HDL) coding examples.

In this chapter we cover the intrinsic versus extrinsic and static versus dynamic timing verification. We present the concept of path delay, which is the fundamental concept in STA. We also discuss timing interface, and an example of interfacing an Intel i960 processor to an EMS EDRAM through an FPGA that acts as the memory controller is presented.